



UCD4015B

Preliminary

CMOS IC

CMOS Dual 4-Stage Static Shift Register

DESCRIPTION

UCD4015B consists of two identical, independent, 4-stage serial-input/parallel-output registers. Each register has independent CLOCK and RESET input as well as a single serial DATA input. "Q" outputs are available from each of the four stages on both registers. All registers stages are D-type, master-slave flip-flops. The logic level present at the DATA input is transferred into the first register stage and shifted over one stage at each positive-going clock transition. Resetting of all stages is accomplished by a high level on the reset line. Register expansion to 8 stages using one UCD4015 package or to more than 8 stages using additional UCD4015's is possible.

FEATURES

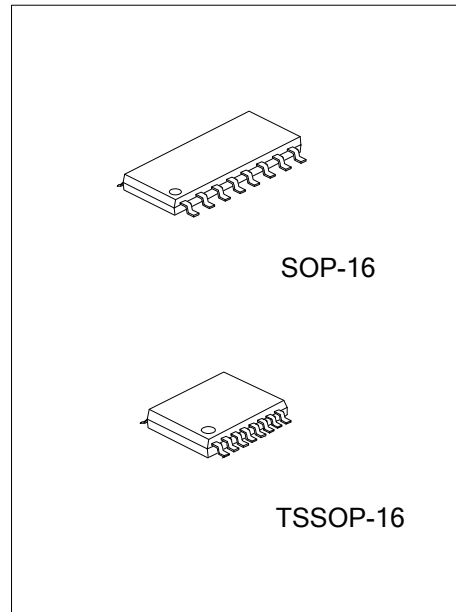
- * 12MHz (typ.) clock rate at 10V
- * Maximum input current of 1µA at 18V
- * Fully static operation
- * 8 master-slave flip-flops plus input and output buffering

APPLICATIONS

- * General-purpose register
- * Serial-input/parallel-output data queueing
- * Serial to parallel data conversion

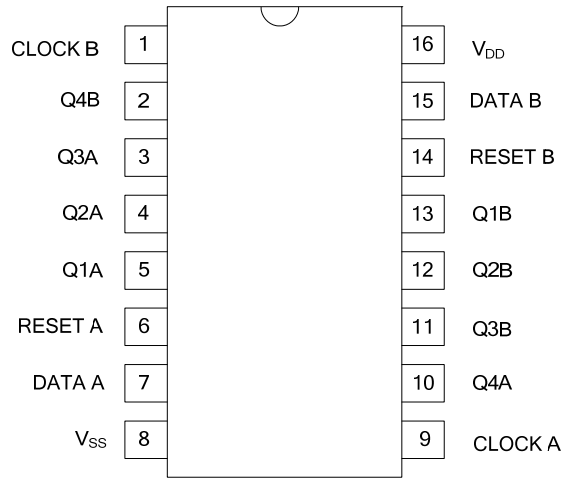
ORDERING INFORMATION

Ordering Number		Package	Packing
Lead Free	Halogen Free		
UCD4015BL-S16-T	UCD4015BG-S16-T	SOP-16	Tube
UCD4015BL-S16-R	UCD4015BG-S16-R	SOP-16	Tape Reel
UCD4015BL-P16-T	UCD4015BG-P16-T	TSSOP-16	Tube
UCD4015BL-P16-R	UCD4015BG-P16-R	TSSOP-16	Tape Reel

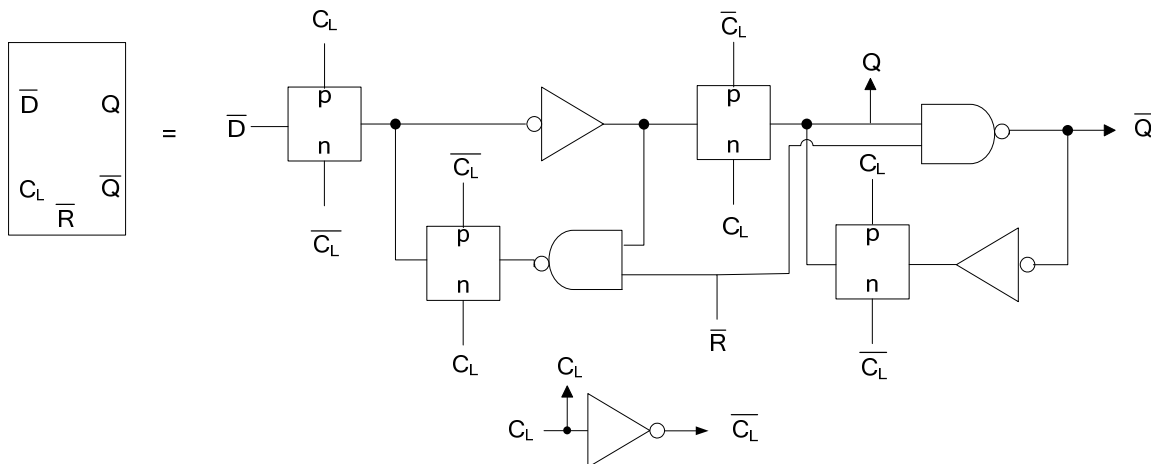
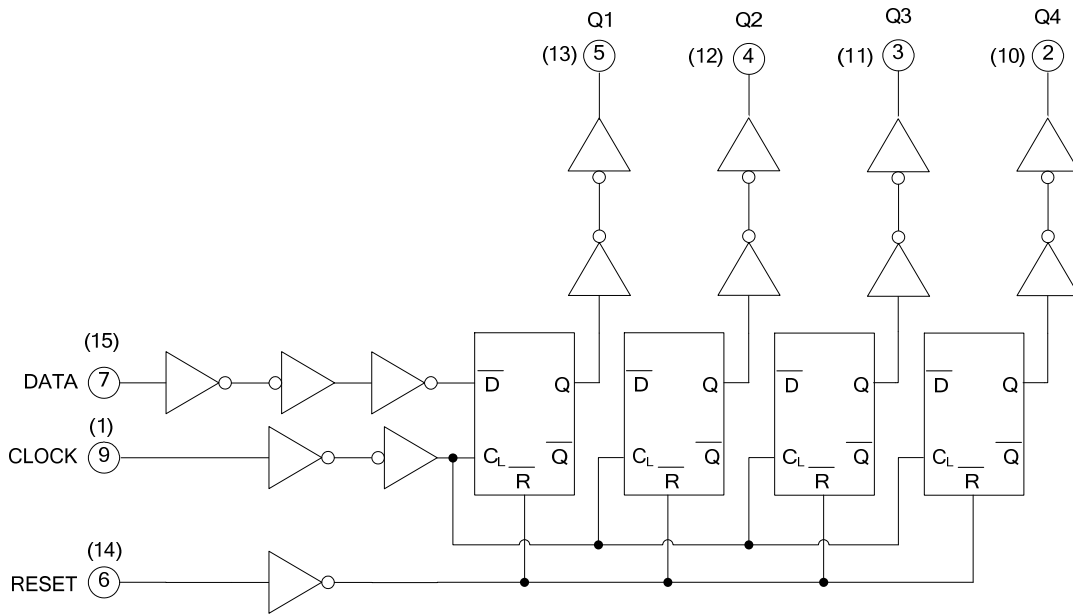


UCD4015BL-S16-R	(1)Packing Type	(1) T: Tube, R: Tape Reel
	(2)Package Type	(2) S16: SOP-16, P16: TSSOP-16
	(3)Lead Free	(3) L: Lead Free, G: Halogen Free




■ PIN CONFIGURATION



■ LOGIC DIAGRAM



■ TRUE TABLE

C_L	D	R	Q_1	Q_n
	0	0	0	Q_{n-1}
	1	0	1	Q_{n-1}
X	X	1	0	0
	X	0	Q_1	Q_n (NC)

Note: X = DON'T CARE CASE, NC = NO CHANGE

■ **ABSOLUTE MAXIMUM RATING** ($T_A = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Supply Voltage	V_{DD}	-0.5 ~ 20	V
Input Voltage	V_{IN}	-0.5 ~ $V_{CC} + 0.5$	V
Output Voltage	V_{OUT}	-0.5 ~ $V_{CC} + 0.5$	V
Input Clamp Current ($V_{IN} < 0$, or $V_{IN} > V_{CC}$)	I_{IK}	± 10	mA
Power Dissipation	P_D	500	mW
	$T_A = -40^\circ\text{C} \sim +85^\circ\text{C}$		
Operating Temperature	T_{OPR}	-40 ~ +125	$^\circ\text{C}$
Storage Temperature	T_{STG}	-65 ~ +150	$^\circ\text{C}$

Note: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

■ **THERMAL DATA**

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	SOP-16	73	$^\circ\text{C/W}$
	TSSOP-16	108	$^\circ\text{C/W}$

■ **RECOMMENDED OPERATING CONDITIONS**

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
Supply Voltage	V_{DD}		3		18	V
Clock Pulse Width	t_w	$V_{DD}=5\text{V}$	180			ns
		$V_{DD}=10\text{V}$	80			
		$V_{DD}=15\text{V}$	50			
Clock Frequency	f_{CL}	$V_{DD}=5\text{V}$			3	MHz
		$V_{DD}=10\text{V}$			6	
		$V_{DD}=15\text{V}$			8.5	
Clock Rise and Fall Time	t_r, t_f	$V_{DD}=5\text{V}$			15	μs
		$V_{DD}=10\text{V}$			6	
		$V_{DD}=15\text{V}$			2	
Data Set-up Time	t_{SU}	$V_{DD}=5\text{V}$	70			ns
		$V_{DD}=10\text{V}$	40			
		$V_{DD}=15\text{V}$	30			

■ **ELECTRICAL CHARACTERISTICS** ($T_A = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Quiescent Supply Current	I_{DD}	$V_{IN}=0, 5\text{V}, V_{DD}=5\text{V}$		0.04	5	μA
		$V_{IN}=0, 10\text{V}, V_{DD}=10\text{V}$		0.04	10	
		$V_{IN}=0, 15\text{V}, V_{DD}=15\text{V}$		0.04	20	
		$V_{IN}=0, 20\text{V}, V_{DD}=20\text{V}$		0.08	100	
Output Low (Sink) Current	I_{OL}	$V_{OUT}=0.4\text{V}, V_{DD}=5\text{V}$	0.51	1		mA
		$V_{OUT}=0.5\text{V}, V_{DD}=10\text{V}$	1.3	2.6		
		$V_{OUT}=1.5\text{V}, V_{DD}=15\text{V}$	3.4	6.8		
Output High (Source) Current	I_{OH}	$V_{OUT}=4.6\text{V}, V_{DD}=5\text{V}$	-0.51	-1		mA
		$V_{OUT}=2.5\text{V}, V_{DD}=5\text{V}$	-1.6	-3.2		
		$V_{OUT}=9.5\text{V}, V_{DD}=10\text{V}$	-1.3	-2.6		
		$V_{OUT}=13.5\text{V}, V_{DD}=15\text{V}$	-3.4	-6.8		
Output Voltage: Low-Level	V_{OL}	$V_{DD}=5\text{V}$		0	0.05	V
		$V_{DD}=10\text{V}$		0	0.05	
		$V_{DD}=15\text{V}$		0	0.05	
Output Voltage: High-Level	V_{OH}	$V_{DD}=5\text{V}$	4.95	5		V
		$V_{DD}=10\text{V}$	9.95	10		
		$V_{DD}=15\text{V}$	14.95	15		

■ ELECTRICAL CHARACTERISTICS(Cont.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Input Low Voltage	V_{IL}	$V_{OUT}=0.5, 4.5V, V_{DD}=5V$			1.5	V
		$V_{OUT}=1, 9V, V_{DD}=10V$			3	
		$V_{OUT}=1.5, 13.5V, V_{DD}=15V$			4	
Input High Voltage	V_{IH}	$V_{OUT}=0.5, 4.5V, V_{DD}=5V$	3.5			V
		$V_{OUT}=1, 9V, V_{DD}=10V$	7			
		$V_{OUT}=1.5, 13.5V, V_{DD}=15V$	11			
Input Leakage Current	$I_{I(LEAK)}$	$V_{IN}=0, 18V, V_{DD}=18V$			± 0.1	μA

■ SWITCHING CHARACTERISTICS ($T_A=25^\circ C$, Input $t_r, t_f=20ns$, $C_L=50pF$, $R_L=200K\Omega$)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
CLOCKED OPERATION						
Propagation Delay Time	t_{PLH} / t_{PHL}	$V_{DD}=5V$		160	320	ns
		$V_{DD}=10V$		80	160	
		$V_{DD}=15V$		60	120	
Transition Time	t_{THL} / t_{TLH}	$V_{DD}=5V$		100	200	ns
		$V_{DD}=10V$		50	100	
		$V_{DD}=15V$		40	80	
Maximum Clock Input Frequency	f_{CL}	$V_{DD}=5V$	3	6		MHz
		$V_{DD}=10V$	6	12		
		$V_{DD}=15V$	8.5	17		
Minimum Clock Pulse Width	t_{WCL}	$V_{DD}=5V$		90	180	ns
		$V_{DD}=10V$		40	80	
		$V_{DD}=15V$		25	50	
Clock Rise and Fall Time	t_{rCL} / t_{fCL}	$V_{DD}=5V$			15	μs
		$V_{DD}=10V$			6	
		$V_{DD}=15V$			2	
Minimum Data Setup Time	t_{SU}	$V_{DD}=5V$		35	70	ns
		$V_{DD}=10V$		20	40	
		$V_{DD}=15V$		15	30	
Minimum Data Hold Time	t_H	$V_{DD}=5V$			0	ns
		$V_{DD}=10V$			0	
		$V_{DD}=15V$			0	
Average Input Capacitance	C_i	Any Input		5	7.5	pF
RESET OPERATION						
Propagation Delay Time	t_{PLH} / t_{PHL}	$V_{DD}=5V$		200	400	ns
		$V_{DD}=10V$		100	200	
		$V_{DD}=15V$		80	160	
Minimum Reset Pulse Width	t_{WR}	$V_{DD}=5V$		100	200	ns
		$V_{DD}=10V$		40	80	
		$V_{DD}=15V$		30	60	

■ TEST CIRCUIT AND WAVEFORMS

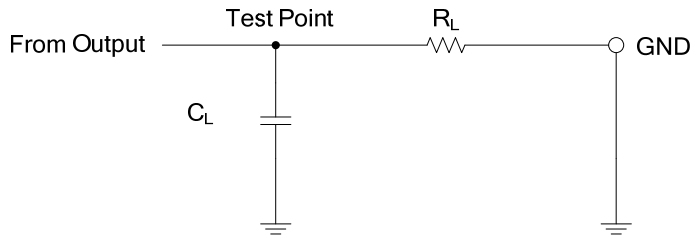


Fig 1. TEST CIRCUIT

Inputs		V_M	V_{LOAD}	C_L	R_L
V_{IN}	t_r, t_f				
V_{DD}	20 ns	$V_{DD}/2$	V_{DD}	50 pF	200 K Ω

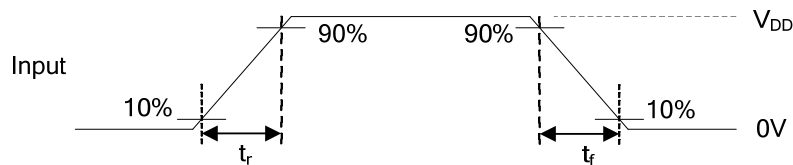


Fig2. VOLTAGE WAVEFORMS INPUT RISE AND FALL TIMES

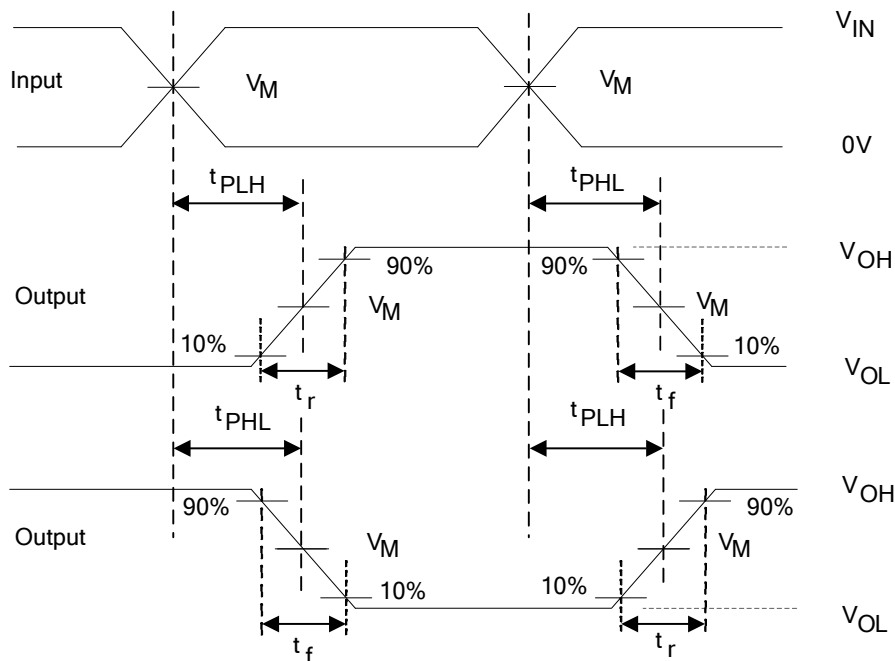


Fig3. VOLTAGE WAVEFORMS PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

- Notes: 1. C_L includes probe and jig capacitance.
 2. All input pulses are supplied by generators having the following characteristics: PRR \leq 1MHz, $Z_O = 50\Omega$.

■ TEST CIRCUIT AND WAVEFORMS(Cont.)

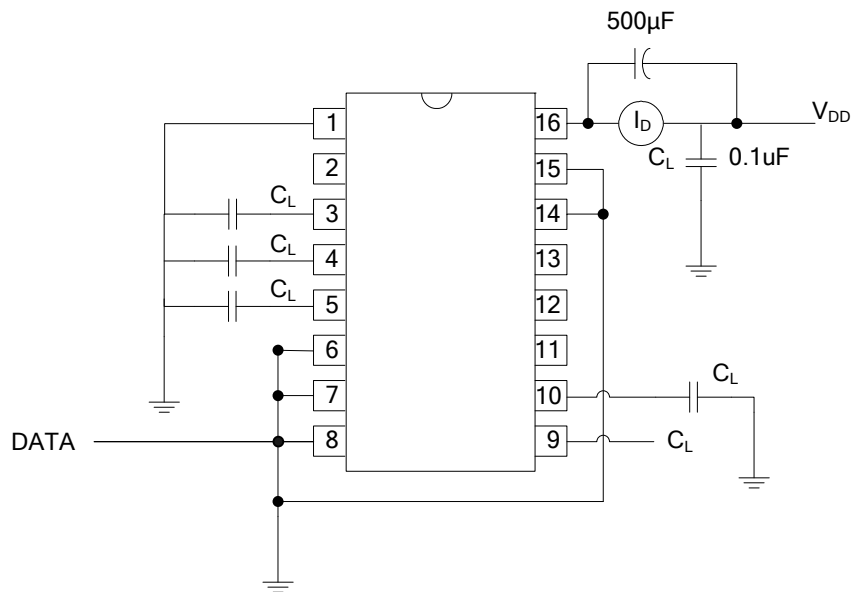


Fig4. Dynamic power dissipation test circuit

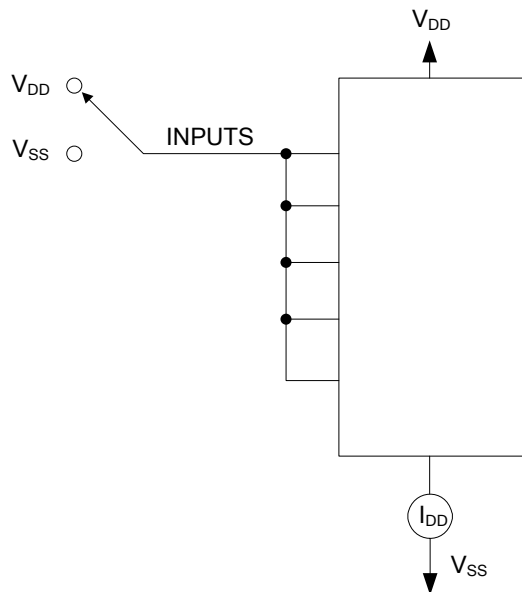


Fig5. Quiescent device current test circuit

■ TEST CIRCUIT AND WAVEFORMS(Cont.)

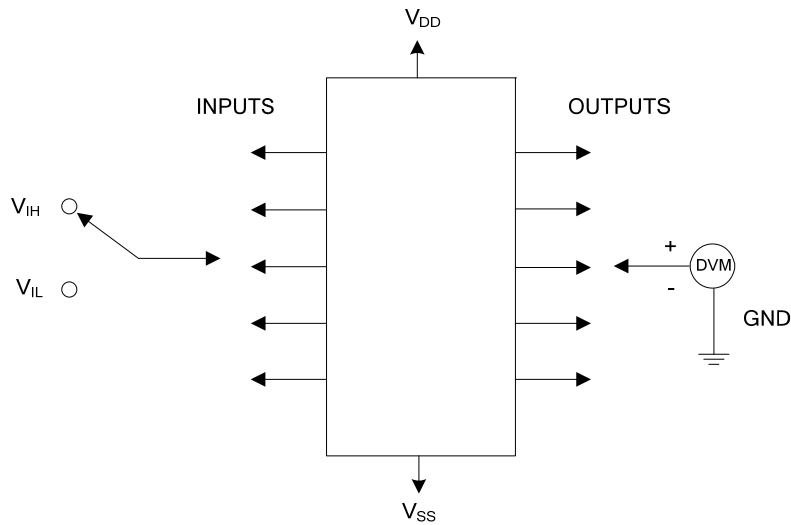


Fig6 Input voltage test circuit

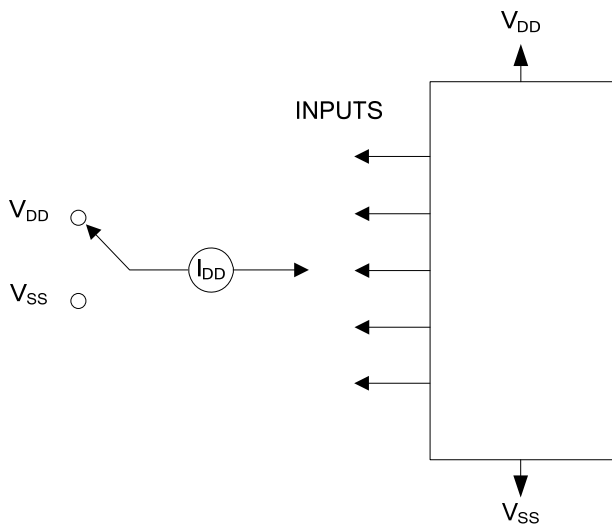


Fig7 Input current test circuit

Note: measure inputs sequentially, to both V_{DD} and V_{SS} ; connect all unused inputs to either V_{DD} or V_{SS} .

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